

TP1 and TP4 testing with compliance boards Mike Dudek JDSU Piers Dawe Avago Technologies

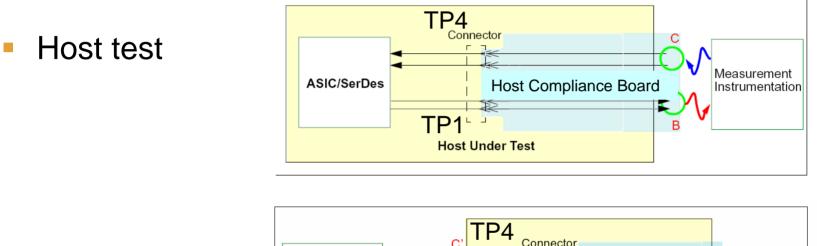
IEEE 802.3ba interim Seoul, Korea Sept 2008

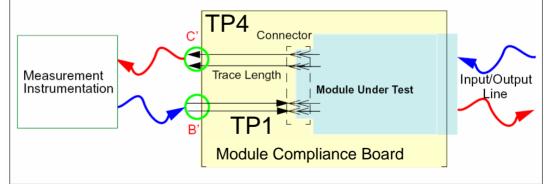
Supporters

- John Petrilla Avago Technologies
- Petar Pepeljugoski IBM
- Ali Ghiasi Broadcom.

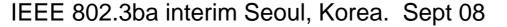


Method typically used for 1GBE





The exact positions of TP1 and TP4 were not well specified in Clause 38





Module test

Comments on previous slide method

- The assumption is that TP1 is equivalent to B on the host testing and B' on the module testing and TP4 is equivalent to C on the host C' on the module. Assumes that the connectors and compliance boards are perfect and lossless
 - OK assumption at 1 GBd, very poor at 10 GBd
- De-embedding the compliance boards is extremely difficult for the key parameters for optical systems
 - jitter including total jitter
 - Eye mask including noise effects
- De-embedding using standard microwave techniques can be used for S-parameter measurements but for simplicity and consistency it is better not to do this for these parameters for the optical system



Purpose of test points

- For compliance testing
 - Must be accessible
 - S-parameters e.g. reflection, transmission specs of a cable
 - Microwave de-embedding is feasible; measurement can be done at a distance to specification point
 - Including sensitivity, eye diagrams and similar with nonlinear electricaloptical converters (PMDs, optical modules)
 - Microwave style de-embedding is not feasible
- For interoperability
 - Must be related to connectors
- For precise results
 - As frequencies increase and higher performance product is specified, have to be more particular about test point definition



Method used in SFF8431(SFP+) and Fibre Channel

- For Outputs: Measure and specify the signals with the compliance board in place.
- For inputs: Calibrate the signals with both compliance boards in place, making the signal more similar to the test for the output signal.
- Compliance boards have fully specified 4 port differential S parameters including crosstalk.
- Note for simplicity in the following diagrams the counter-flow signals that create crosstalk are not shown. However in practice they are included.

References.

- SFF-8431 (<u>ftp://ftp.seagate.com/sff/</u>)
- Fibre Channel Physical interface-4 (FC-PI-4) <u>http://www.t11.org/t11/docreg.nsf/alldrflat?OpenView&startkey=FC-PI-4&expandview</u>





Test point definitions 1/2

- TP1, TP2, TP3, TP4 in Clause 38 (Gigabit Ethernet) is well known
 - TP1, electrical: host output, module input
 - TP2, module optical output
 - Actually, 2 m after the MDI
 - TP3: module optical input
 - TP4, electrical: module output, host input
 - TP0, TP5 have been used informally for a some time (at IC within host)
- Clause 39, CX4, also has TP1, TP2, TP3, TP4 (all electrical)
 - TP1: upstream of transmit MDI
 - TP2: just downstream of transmit MDI
 - TP3: just upstream of receive MDI
 - TP4: downstream of receive MDI
 - "It is expected that in many implementations TP1 and TP4 will be common between 1000BASE-SX (Clause 38), 1000BASE-LX (Clause 38), and 1000BASE-CX"

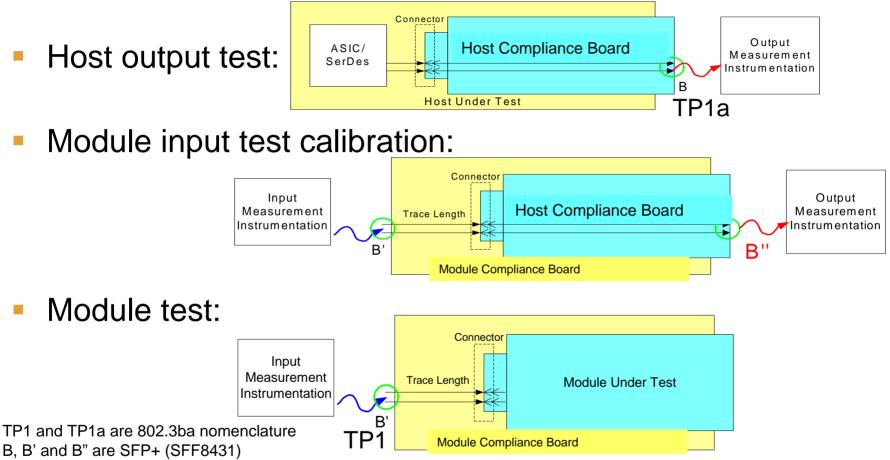


Test point definitions 2/2

- Fibre Channel up to 4GFC has alpha gamma delta ($\alpha_T \delta_T \gamma_T \gamma_R \delta_R \alpha_R$)
 - For an optical link,
 - α_T : Output of IC in host
 - δ_T : host output, module input, just downstream of module transmit electrical connector
 - $-\gamma_T$: module optical output, 2 m after the MDI
 - $-\gamma_R$: module optical input
 - $\delta_{\rm R}$: module output, host input, just downstream of module receive electrical connector
- For 8GFC, "just downstream" is taken to mean the input or output of a compliance board with a defined electrical loss
- SFP+ is the same as 8GFC but with different names
- XFP is an earlier, less thorough, version of SFP+



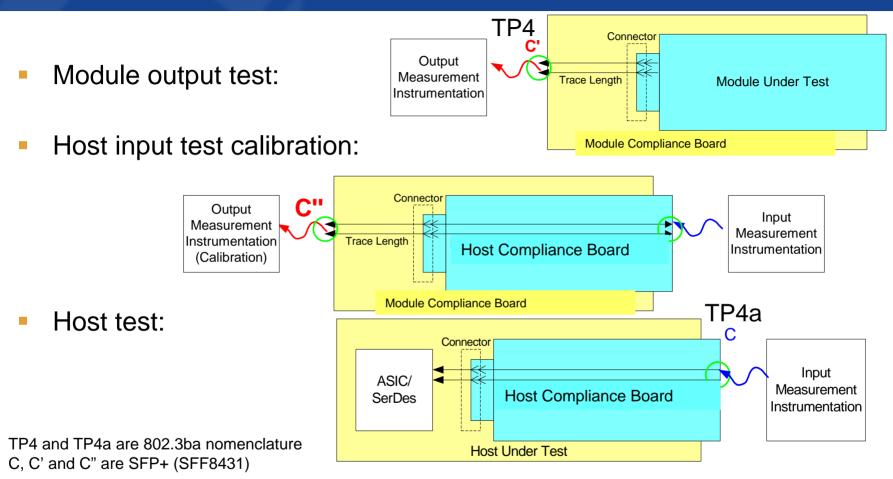
Example for Host output/module input



- Advantage: By specifying the input signal calibration at B" the connector and compliance test board degradations are calibrated out
 - Note that change from calibration to test requires no disconnection of SMA connections
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Example for module output/host input

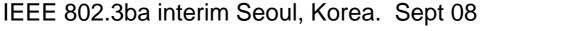


- Advantage: By specifying the input signal calibration at C" the Connector and compliance test board degradations are calibrated out
 - Note that change from calibration to test requires no disconnection of SMA connections



Test points for different sublayers 1/2

- Untimed optical module
 - Use methodology established in SFP+ and 8GFC
- 10GBASE-CR4, 10GBASE-CR10
 - Compatible with above
 - In practice, implementers can choose whether to use specified compliance boards or their own, because CR specs can be de-embedded from one end of a compliance board to the other
- Optical module with CDRs
 - Annex 153A XLAUI / CAUI (nAUI for short) is XFP's XFI electrical interface with some second thoughts
 - But it doesn't yet show the connector
 - Use same test points and electrical compliance board specs as for unretimed optical module
 - TP1 and TP4 spec numbers will differ





Test points for different sublayers 2/2

- Other *n*AUI
 - For a pair of ICs to be soldered on a board without a connector, e.g. PCS chip and FEC connected by *n*AUI
 - Assess the ICs on demo boards, sum of trace lengths/losses to equal or exceed target trace length/loss
 - May be able to give some credit (in extra length or loss) for the absence of a connector
- 40GBASE-KR4
 - Have to decide if we want interoperability
 - If so, use compliance board methodology but different connectors may imply different electrical specs (e.g. for reflection and crosstalk)
 - TP0, TP5 at ASIC to be informative
 - TP1-4 related to connector, normative
- Recommend that we revisit the test point Ad Hoc to discuss this further



